

FDFMA2P859T

July 2009

Integrated P-Channel PowerTrench® MOSFET and Schottky Diode

-20 V, -3.0 A, 120 mΩ

Features

MOSFET:

- Max $r_{DS(on)}$ = 120 m Ω at V_{GS} = -4.5 V, I_D = -3.0 A
- \blacksquare Max $r_{DS(on)}$ = 160 m Ω at V_{GS} = –2.5 V, I_D = –2.5 A
- Max $r_{DS(on)}$ = 240 m Ω at V_{GS} = -1.8 V, I_D = -1.0 A

Schottky:

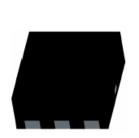
- V_F < 0.54 V @ 1 A
- Low profile 0.55 mm maximum in the new package MicroFET 2x2 Thin
- Free from halogenated compounds and antimony oxides
- RoHS compliant

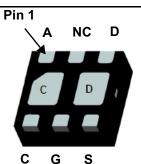


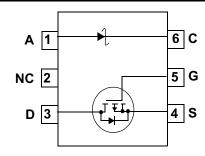
General Description

This device is designed specifically as a single package solution for the battery charge switch in cellular handset and other ultra-portable applications. It features a MOSFET with low on-state resistance and an independently connected low forward voltage schottky diode for minimum conduction losses.

The MicroFET 2x2 **Thin** package offers exceptional thermal performance for its physical size and is well suited to linear mode applications.







MicroFET 2x2 Thin

MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain to Source Voltage		20	V
V_{GSS}	Gate to Source Voltage		±8	V
	Drain Current -Continuous	(Note 1a)	-3	
ID	-Pulsed		-6	Α
Б	Power Dissipation	(Note 1a)	1.4	W
P_{D}	Power Dissipation	(Note 1b)	0.7	vv
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C
V_{RRM}	Schottky Repetitive Peak Reverse Voltage		30	V
Io	Schottky Average Forward Current		1	Α

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	86	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1b)	173	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1c)	86	C/VV
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1d)	140	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
59	FDFMA2P859T	MicroFET 2x2 Thin	7 "	8 mm	3000 units

Electrical Characteristics $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	octeristics					
BV_DSS	Drain to Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$	-20			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I_D = -250 μ A, referenced to 25 °C		-12		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -16 V, V _{GS} = 0 V			-1	μА
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 8 \text{ V}, \ V_{DS} = 0 \text{ V}$			±100	nA

On Characteristics

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = -250 \mu A$	-0.4	-0.7	-1.3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = -250 μ A, referenced to 25 °C		2		mV/°C
		$V_{GS} = -4.5 \text{ V}, I_D = -3.0 \text{ A}$		90	120	
		$V_{GS} = -2.5 \text{ V}, I_D = -2.5 \text{ A}$		120	160	
r _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = -1.8 \text{ V}, I_D = -1.0 \text{ A}$		172	240	mΩ
		$V_{GS} = -4.5 \text{ V}, I_D = -3.0 \text{ A}$ $T_J = 125 ^{\circ}\text{C}$		118	160	
9 _{FS}	Forward Transconductance	$V_{DS} = -5 \text{ V}, I_D = -3.0 \text{ A}$		7		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V = 10 V V = 0 V	435	pF
C _{oss}	Output Capacitance	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz	80	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1.0 WH 12	45	pF

Switching Characteristics

t _{d(on)}	Turn-On Delay Time		9	18	ns
t _r	Rise Time	$V_{DD} = -10 \text{ V}, I_D = -1.0 \text{ A}$	11	19	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = -4.5 \text{ V}, R_{GEN} = 6 \Omega$	15	27	ns
t _f	Fall Time		6	12	ns
$Q_{g(TOT)}$	Total Gate Charge	V - 40 V I - 20 A	4	6	nC
Q_{gs}	Gate to Source Gate Charge	V_{DD} = -10 V, I_{D} = -3.0 A V_{GS} = -4.5 V	0.8		nC
Q_{gd}	Gate to Drain "Miller" Charge	V GS = -4.5 V	0.9		nC

Drain-Source Diode Characteristics

IS	Maximum Continuous Drain-Source Diode Forward Current				Α
V_{SD}	Source to Drain Diode Forward Voltage $V_{GS} = 0 \text{ V}, I_S = -1.1 \text{ A}$ (Note 2)	2)	-0.8	-1.2	V
t _{rr}	Reverse Recovery Time		17		ns
Q_{rr}	Reverse Recovery Charge		6		nC

Schottky Diode Characteristics

			T _J = 25 °C	0.3	1.0	μΑ
I_R	Reverse Leakage	V _R = 10 V	T _J = 85 °C	25	40	μΑ
			T _J = 125 °C	0.28	0.37	mA
			T _J = 25 °C	1.0	2.5	μΑ
I_R	Reverse Leakage	V _R = 20 V	T _J = 85 °C	74	110	μА
			T _J = 125 °C	0.73	1.00	mA
			T _J = 25 °C	0.40	0.41	V
V_{F}	Forward Voltage	I _F = 100 mA	T _J = 85 °C	0.31	0.33	V
			T _J = 125 °C	0.26	0.27	V
			T _J = 25 °C	0.52	0.54	V
V_{F}	Forward Voltage	I _F = 1 A	T _J = 85 °C	0.45	0.47	V
			T _J = 125 °C	0.41	0.43	V

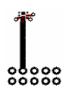
Electrical Characteristics T_A = 25 °C unless otherwise noted

Notes:

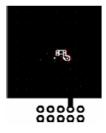
- 1: $R_{\theta JA}$ is determined with the device mounted on a 1 in² oz. copper pad on a 1.5 x 1.5 in. board of FR-4 material. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.
 - (a) MOSFET $R_{\theta JA}$ = 86 °C/W when mounted on a 1 in² pad of 2 oz copper, 1.5 " x 1.5 " x 0.062 " thick PCB.
 - (b) MOSFET $R_{\theta JA}$ = 173 °C/W when mounted on a minimum pad of 2 oz copper.
 - (c) Schottky R_{0,JA} = 86 °C/W when mounted on a 1 in² pad of 2 oz copper, 1.5 " x 1.5 " x 0.062 " thick PCB.
 - (d) Schottky $R_{\theta JA}$ = 140 $^{o}\text{C/W}$ when mounted on a minimum pad of 2 oz copper.



a)86 °C/W when mounted on a 1 in² pad of 2 oz copper.



b)173 °C/W when mounted on a minimum pad of 2 oz copper.



c)86 °C/W when mounted on a 1 in² pad of 2 oz copper.



d)140 °C/W when mounted on a minimum pad of 2 oz copper.

2: Pulse Test: Pulse Width < 300 μs, Duty cycle < 2.0%.

Typical Characteristics T_J = 25 °C unless otherwise noted

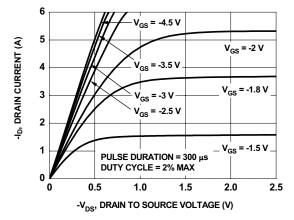


Figure 1. On-Region Characteristics

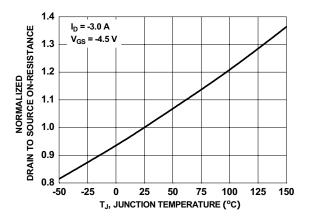


Figure 3. Normalized On-Resistance vs Junction Temperature

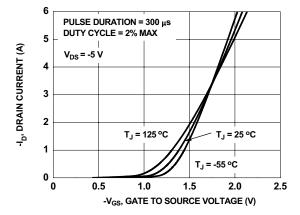


Figure 5. Transfer Characteristics

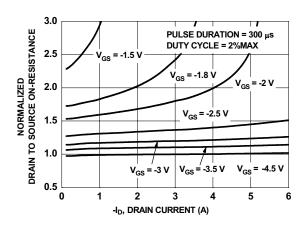


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

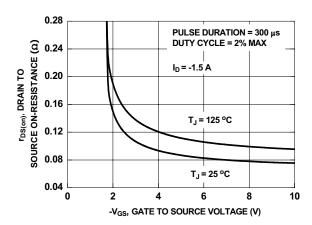


Figure 4. On-Resistance vs Gate to Source Voltage

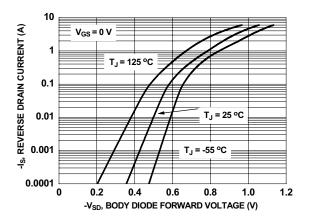


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics $T_J = 25$ °C unless otherwise noted

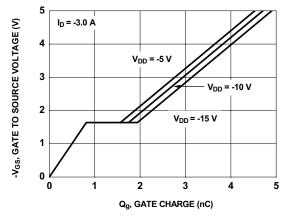


Figure 7. Gate Charge Characteristics

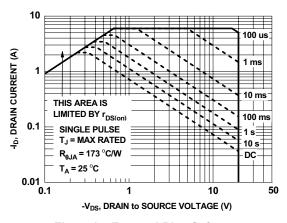


Figure 9. Forward Bias Safe Operating Area

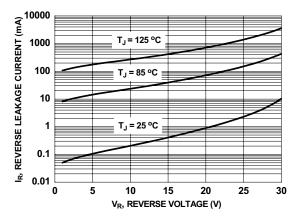


Figure 11. Schottky Diode Reverse Current

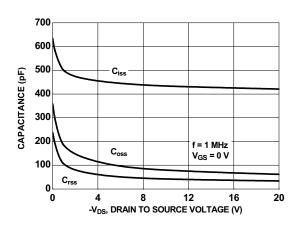


Figure 8. Capacitance vs Drain to Source Voltage

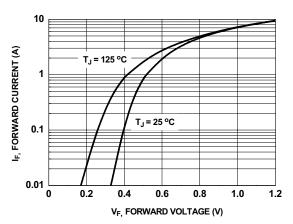


Figure 10. Schottky Diode Foward Voltage

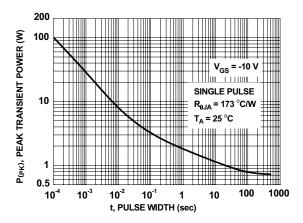


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics $T_J = 25$ °C unless otherwise noted

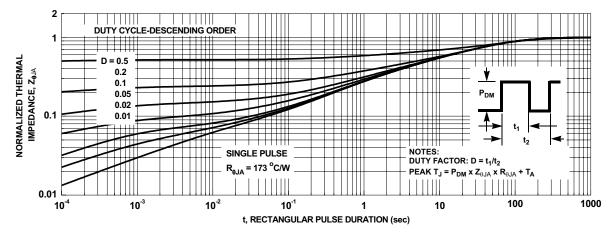
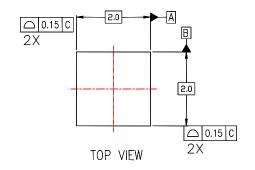
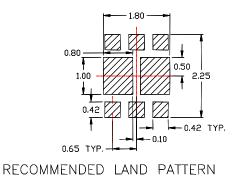
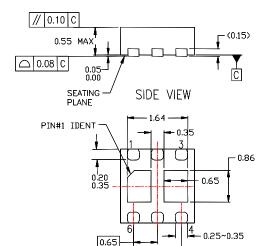


Figure 13. Junction to Ambient Transient Thermal Response Curve

Dimensional Outline and Pad Layout







BOTTOM VIEW

1.30 0.10(M)CAB

NOTES:

A. NON CONFORMS TO JEDEC REGISTRATION MO-288,

0.65

- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994

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